A study of TES X-ray microcalorimeter array with different absorber thickness towards the observation from 50 eV to 15 keV for STEM-EDS

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Microanalysis of astromaterials using STEM-EDS

Astromaterials are known to keep informations about early phase solar system!

Meteorites have

- sub-micro scale structures
- many elements such as **B**, C, O, **Si**, Mg, **Fe**...

From the amount of B(=183eV) in the silicate, we can investigate the effect of solar wind.

We have to know the amount of B and Si by the quantitative analysis (W.FUJIYA+2016)

Method of Microanalysis

• STEM-EDS can obtain the image and composition from meteorites.



2

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Scanning Transmission Electron Microscope

EDS : Energy Dispersive X-ray Spectroscopy



STEM TES EDS system and performance





We were able to...

- ✓ detect an emission line of CuL α , SiK β , MgK β
- ✓ detect a self absorption of specimen
- ✓ resolve the continuum and the line emissions

Detection limit in the low energy band

• In old system, it is difficult to detect a low energy X-ray below 300 eV.

Low energy band sensitivity is limited by

- the background level
- an absorption of the OBF (OBF:optical blocking filter)
- fluorescence yields of elements



Energy spectrum of BN specimen



Compatibility between the high and the low energy band

- We need to increase the signal to noise ratio by improving energy resolution, because other factors are difficult to change.
- To improve the DL 10% Δ E needs to improve below 4 eV
- Decreasing the C or Tc for improving ΔE

 $\Delta E \propto \sqrt{k_B T^2 C}$

- However decreasing of C or Tc makes the energy band narrow
- We set two different types of TES on single device for covering low energy band and high energy band

$$S/N = \frac{S}{\sqrt{S + \Delta Eb(1 + \epsilon)/2.35}},$$

 ΔE : energy resoltution (eV),

b: Backgroud level (counts/eV),

S : signal intensity (counts), ϵ : fudge factor ~ 1

background level



Broadening of X-ray on the TES chip Takano et al., 2017

3500

2500

1500

500

- An X-ray photon from specimen is collected by **poly-capillary optics**
- The refraction of the poly-capillary depends on the energy
- Spread of the low energy X-ray is broader than high energy on TES chip

Simulation of count map

LTD18,2

1.8 mm 164 c 346 с 373 c 846 c 644 c 373 c 846 c 1462 c 845 c 1460 c 1920 c 1921 c 644 c 1462 c 642 c 2524 c 1459 c 2522 c 3316 c 3317 c 846 c 1921 c 844 c 3317 c 1917 c 3313 c 4356 c 4358 c 846 c 844 c 1920 c 3316 c 1917 c 3312 c 4355 c 4356 c 643 c 1460 c 642 c 2519 c 3313 c 2522 c 1458 c 3312 c 372 c 1917 c 1459 c 845 c 371 c 1458 c 1917 c 843 c 642 c 844 c 844 c 642 c 371 c 372 c



Concept design

- In high energy bands, the centroid 12 pixels occupied about 80% of total counts.
- In low energy bands, the outside 52 pixels occupied about 60% of total counts.
- In order to satisfy both high and low energy, the TES for low energy needs to be located at the outer side on the chip



1.5

1.0

0.5

0.0

[mm]

 \succ

Low energy

60%

High enel

80%

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1.5

1.0

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0.0

-0.5

Y [mm]

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60%

High energ

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Fabrication of a test device with two different type absorbers

- We set the thin absorber of 300 nm to satisfy requirement of the ΔE , Esat
- For demonstration, we located the 12 thin absorbers to occupy about 20% of total counts.
- In order to realize two different type absorbers, the thin absorber was formed first and then the thick absorber was formed.



Fabrication results

- ✓ We were able to fabricate two different type absorbers with the target thickness
- ✓ We established the process that fabricate the thin absorber and thick absorber on a single chip.



Conclusion

- Towards the microanalysis of astromaterials for our solar system, we have been developing the STEM-TES-EDS system.
- In the low energy band below 500 eV, old system is low sensitivity.
- We suggested the concept design of TES with two different absorber thickness to increase sensitivity in low energy band.
 - TES pixels of the low E band were located out side.
 - TES pixels of the high E band are centroid 12 pixel.
 - We controlled the absorber thickness to degrease C without changing the geometry of pixel.
- We fabricated test device to confirm the performance of the TES with 2 different type absorber thickness.

Future plans

- We'll fabricate the concept design TES and evaluate its performance by EDS system.
- We would like to analyze the Hayabusa-2 sample using this new system at 2020!

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Thank you for your attention!

Detection Efficiency

- We calculated the detection efficiency by considering optical path
- The florescent X-rays emitted from the sample
- → X-ray poly capillary (throughput)
- → X-ray window/filters (Transmission efficiency of Al/polyamide)
- → Detection efficiency of the TES (quantum efficiency of Au)





Optimization of the thin absorber thickness

Requirements for thickness

- Esat > 2.0 keV (B (Li) Si)
- $\Delta E < 2 \text{ eV}$
- Quantum efficiency > 99%
- There is an absorption edge of Au at 0.15 keV
- We adopted thickness of 300 nm





Tc = I30 mK

STEM TES EDS system and it's performance





We were able to...

- ✓ detect an emission line of CuLα, SiKβ, MgKβ
- ✓ detect a self absorption of specimen
- ✓ resolve the continuum and the line emissions
- $\checkmark \Delta E < 10 \text{ eV} @AlK \alpha \text{ under } 4.5 \text{ kcps}$